

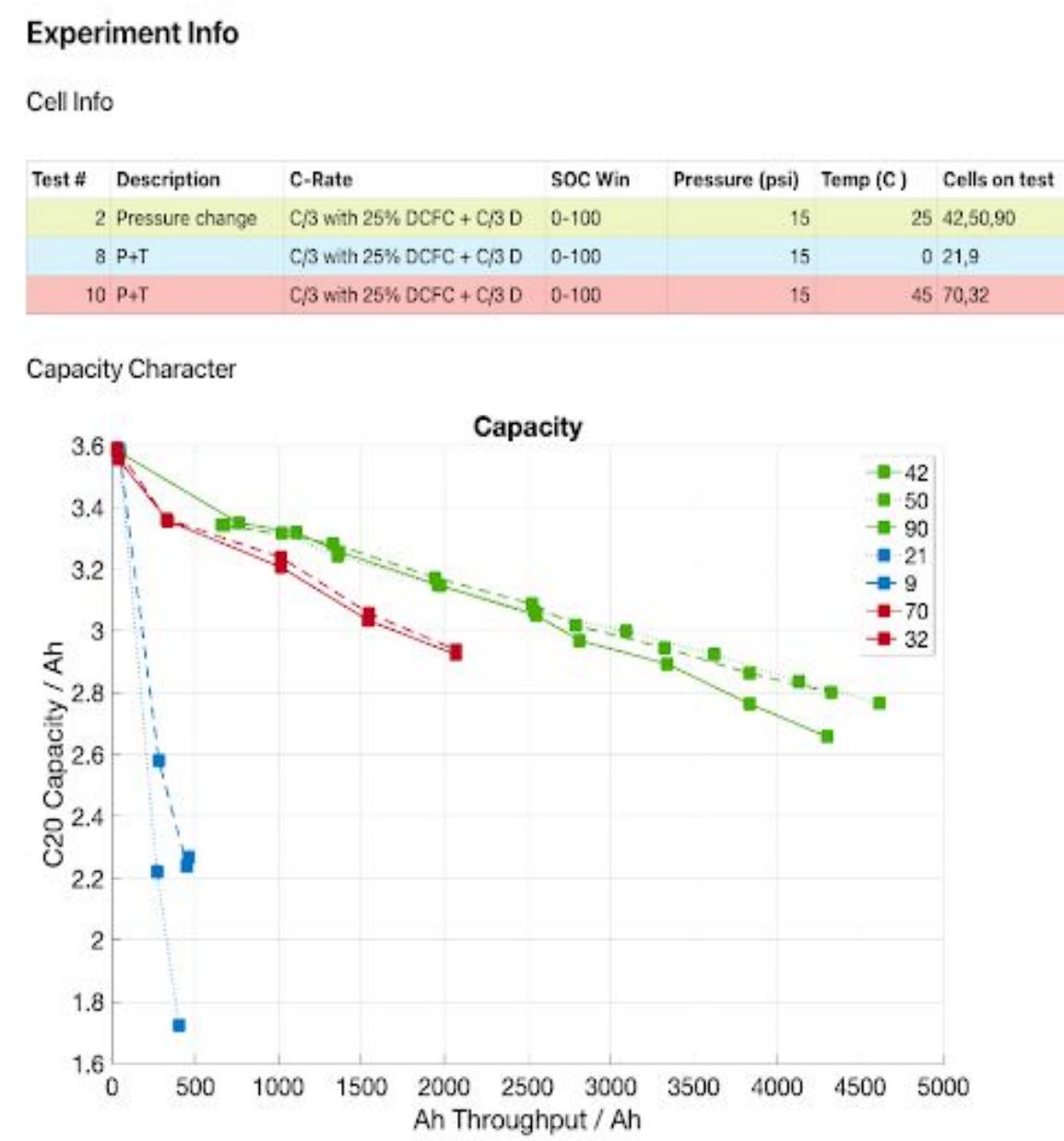
Physics-Constrained Parameter Identification for Electrochemical Impedance Spectroscopy Modeling

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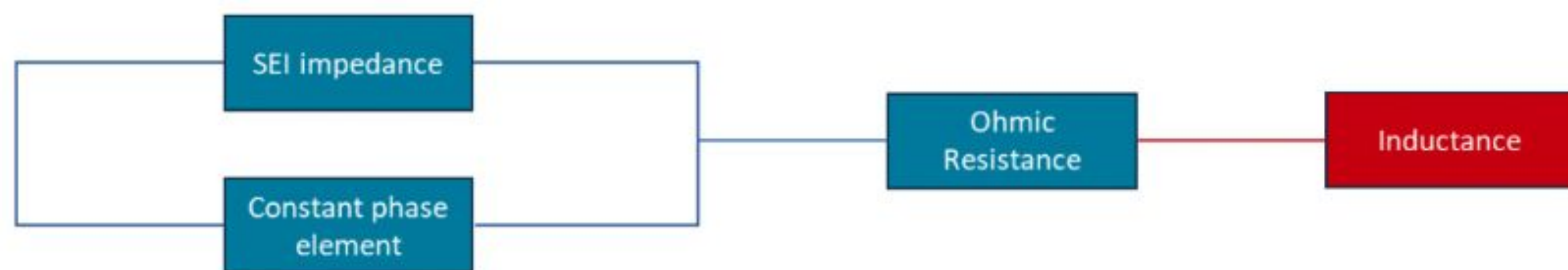
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Overview

- Problem:** Conventional equivalent circuit models (ECMs) for EIS fitting lack physical interpretability. Full physics models contain 20+ parameters and are too complex to solve for on-board BMS applications
- Idea:** Hybrid model combining a physics-based transmission-line SEI impedance with compact ECM elements (R_0 , L_s), fitted via physics-constrained differential evolution



Physics-based Model Architecture



Input: frequency (roughly from 10 Hz to 10 kHz)
Output: Impedance

[1]

$$Z_{SEI,I} = \frac{L_{SEI}}{a_n l_n A_n \sigma_{SEI}} + \frac{1}{a_n l_n A_n \sigma_{SEI} \sqrt{\frac{s}{D_{SEI}}}} \frac{(1 - \cosh(\sqrt{\frac{s}{D_{SEI}}} L_{SEI}))}{\sinh(\sqrt{\frac{s}{D_{SEI}}} L_{SEI})}$$

$$Z_{SEI} = \frac{Z_{SEI,I}}{1 + s Z_{SEI,I} Z_{SEI,CPE}}$$

$$Z_{SEI,CPE} = \frac{1}{s^n Q_{SEI}}$$

$$s = j\omega$$

Known design parameters – a : specific surface area, l : electrode thickness, A : electrode area

Unknown parameters – L : thickness of the SEI/CEI film; σ : conductivity of the SEI film, D : Diffusivity in film,

Q & n : capacitance and the factor of Constant Phase Element (CPE),

R_0 : ohmic resistance in series

L_s : inductance in series

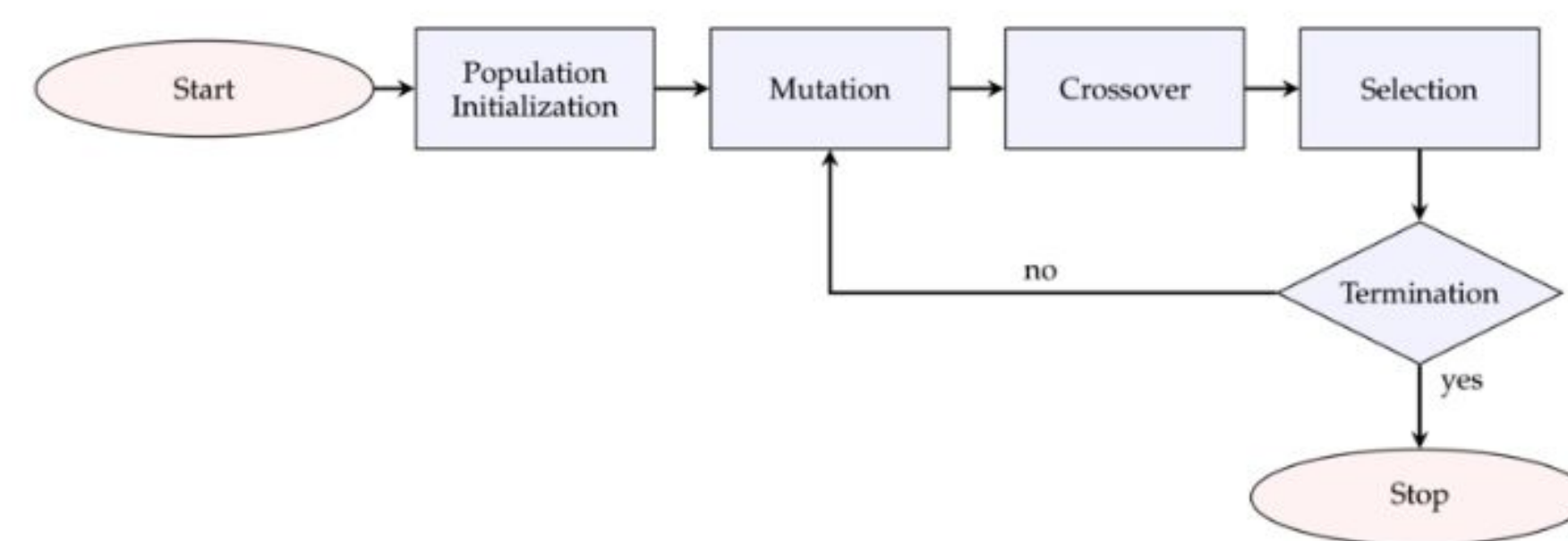
- ECM section:** Fixed series inductance $L_s = 107.78$ nH + ohmic resistance R_0
- Physics-based section:** Transmission-line SEI impedance Z_{SEI} governed by 5 physical parameters

Methodology

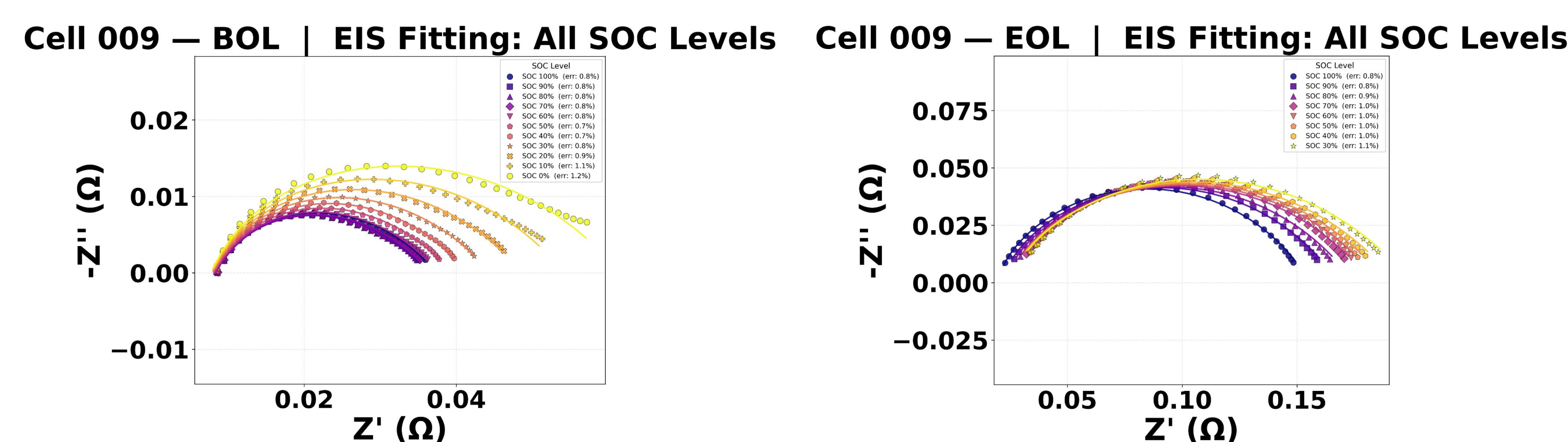
- Cost Function Selection**
 - 5 candidates evaluated; hybrid step weighting selected
 - Highest-frequency points weighted 10x; 2x weight on imaginary component

$$\mathcal{L}(\theta) = \sum_k w_k \left(Z'_{exp}(f_k) - Z'_{sim}(f_k) \right)^2 + 2 \sum_k w_k \left(Z''_{exp}(f_k) - Z''_{sim}(f_k) \right)^2$$

- Differential Evolution Optimiser**
 - Global, gradient-free optimiser: robust for the non-convex, multi-decade parameter landscape
 - Parameters spanning orders of magnitude (L , D , σ) optimised in \log_{10} -space
 - Local L-BFGS-B polish applied to final solution for precise convergence

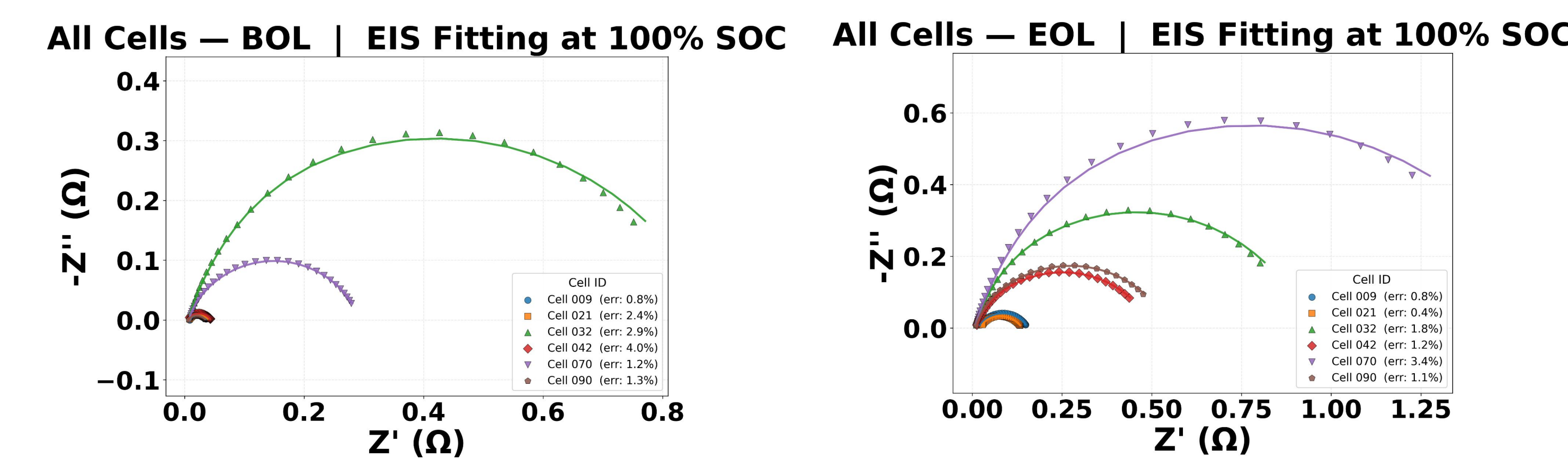


- Multi-SOC Constraint Strategy (6 → 3 free parameters)**
 - Fit highest SOC with all 6 parameters free
 - Fix L_{SEI} , D_{SEI} , R_0 across remaining SOCs (material/structural i.e., SOC-invariant)
 - Allow σ , C , n to vary (transport/capacitive i.e., weakly SOC-dependent)
- Degradation Constraints**
 - $L_{SEI}(EOL) \geq L_{SEI}(BOL)$: SEI grows with cycling
 - $R_0(EOL) \geq R_0(BOL)$: ohmic resistance increases with aging

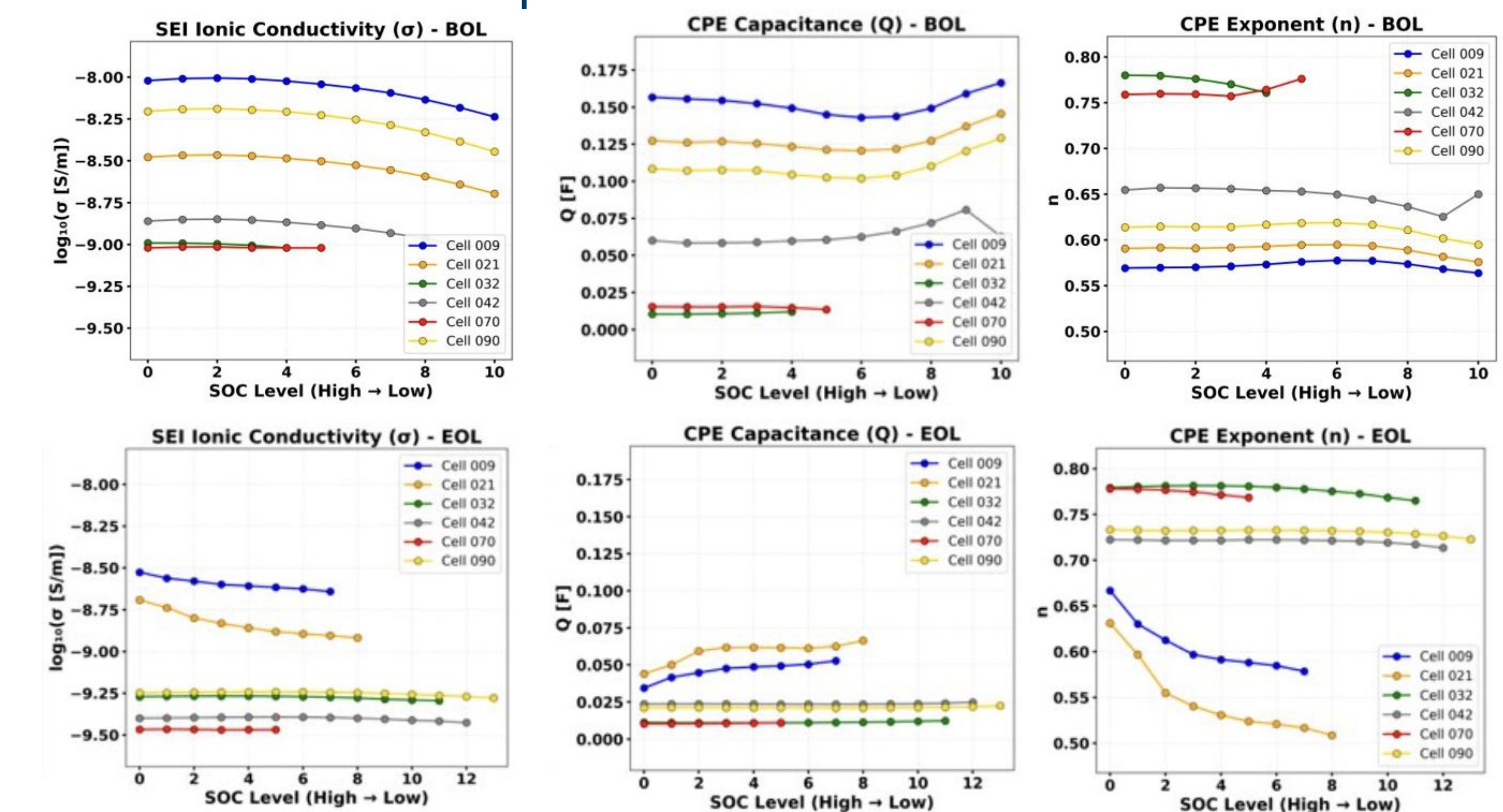


Experimental Results

- 1.7% average MAPE over 119 EIS tests - simulations match experimental data
- 11 SOC levels fitted in 37.5 s



- Studied temperature dependence - higher temp. results in higher SEI impedance
- Studied SEI parameter sensitivity; separate parameter trends across multiple SOC levels



Conclusions

- Hybrid physics+ECM model reproduces EIS across 6 cells × 2 SOHs × 10 SOCs with **mean 1.77% error**
- Degradation constraints ($L \uparrow$, $R_0 \uparrow$) ensure **physically consistent** BOL→EOL trends in all 6 cells
- Multi-SOC constraint strategy reduces free parameters from **6 → 3**, improving efficiency and consistency
- Future work:** extending to additional electrochemical process and combining with degradation modeling